

# Applied Physics A

## Solids and Surfaces

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## Contents

### Invited Papers

Campisano, S.U.: Non-Equilibrium Dopants Incorporation in Silicon Melted by Laser Pulses .....	195
Kohl, C.D.: Electrical Properties of Semiconductor Surfaces ..	127
Weber, E.R.: Transition Metals in Silicon .....	1

### Contributed Papers

Aldi, G., Dupasquier, A., Regazzoni, C.: The Differential Method for the Study of Small Variations of Positron Lifetime Spectra .....	51
Algra, H.A., Hansen, P.: Variation of the Saturation Magnetization Through a Neon Implanted YIG Film .....	63
Azema, A., see Falco, C., et al. ....	23
Baczewski, L.T., Lipiński, E.: Mechanical Properties of Co-Si-B Amorphous Alloys .....	213
Bäuerle, D., Leyendecker, G., Wagner, D., Bauser, E., Lu, Y.C.: Laser Grown Single Crystals of Silicon .....	147
Bäuerle, D., see Leyendecker, G., et al. ....	237
Bail, B., see Dormann, E., et al. ....	227
Bauser, E., see Bäuerle, D., et al. ....	147
Bertolotti, M., see Vitali, G., et al. ....	161
Besocke, K., see Hofer, W.O., et al. ....	83
Bömmel, H.E., see Stachel, M. ....	27
Botineau, J., see Falco, C., et al. ....	23
Conzelmann, H., Graff, K., Weber, E.R.: Chromium and Chromium-Boron Pairs in Silicon .....	169
Deb Roy, M., Nag, B.R.: Hot Electron Diffusion in CdTe ..	189
Doppelbauer, J., see Leyendecker, G., et al. ....	237
Dormann, E., Sachs, G., Stöcklein, W., Bail, B., Schwoerer, M.: Gaussmeter Application of an Organic Conductor ..	227
Dupasquier, A., see Aldi, G., et al. ....	51
Ennen, H., see Windscheif, J., et al. ....	47
Falco, C., Botineau, J., Azema, A., Micheli, M. de, Ostrowsky, D.B.: Optical Properties Determination at 10.6 $\mu\text{m}$ of Thin Semiconducting Layers .....	23
Figielski, T., see Wosiński, T., et al. ....	233
Fischer, A., see Künzel, H., et al. ....	73
Freund, F., see Kathrein, H., et al. ....	33
Geittner, P., see Leyendecker, G., et al. ....	237
Godlewski, M., Przybylińska, H., Langer, M.J.: On the Determination of Thermal Ionization Energy of Deep Centers from ESR Data .....	105
Gonska, H., see Kathrein, H., et al. ....	33
Graff, K., see Conzelmann, H., et al. ....	169
Hansen, P., see Algra, H.A. ....	63
Hillenbrand, B., see Krause, N., et al. ....	67
Hofer, W.O., Besocke, K., Stritzker, B.: A Search for a Thermal Spike Effect in Sputtering. II. Temperature Dependence of the Yield for Heavy Atomic and Molecular Ion Bombardment .....	83
Ibach, H., see Kirschner, J., et al. ....	177
Jantz, W., Koidl, P., Wettling W.: Elastic, Optical, and Non-linear Optical Properties of InP <sub>3</sub> .....	109
Kang, N.K., Swanson, L.W.: Computer Simulation of Liquid Metal Ion Source Optics .....	95
Kathrein, H., Gonska, H., Freund, F.: Subsurface Segregation and Diffusion of Carbon in Magnesium Oxide .....	33
Kaufmann, U., see Windscheif, J., et al. ....	47
Kimura, T., see Windscheif, J., et al. ....	47
Kirschner, J., Oepen, H.P., Ibach, H.: Energy- and Spin-Analysis of Polarized Photoelectrons from NEA GaAsP .....	177
Knecht, J., see Künzel, H., et al. ....	73

Koidl, P., see Jantz, W., et al. ....	109
Krause, N., Hillenbrand, B., Uzel, Y., Schnitzke, K.: Superconducting Properties and Limitations of Thin-Wall Niobium and Niobium Tin Cavities .....	67
Krause, N., see Uzel, Y., et al. ....	185
Künzel, H., Fischer, A., Knecht, J., Ploog, K.: A New Semiconductor Superlattice with Tunable Electronic Properties and Simultaneously with Mobility Enhancement of Electrons and Holes .....	73
Kuhnert, R., see Peschel, W., et al. ....	59
Langer, J.M., see Godlewski, M., et al. ....	105
Lee, Y., see Wang, Y., et al. ....	123
Leyendecker, G., see Bäuerle, D., et al. ....	147
Leyendecker, G., Doppelbauer, J., Bäuerle, D., Geittner, P., Lydtin, H.: Raman Diagnostics of CVD Systems: Determination of Local Temperatures .....	237
Lipiński, E., see Baczewski, L. T. ....	213
Lizzio, R., see Stagni, L. ....	217
Lu, Y.C., see Bäuerle, D., et al. ....	147
Lydtin, H., see Leyendecker, G., et al. ....	237
Marinelli, M., see Vitali, G., et al. ....	161
Micheli, M. de, see Falco, C., et al. ....	23
Morawski, A., see Wosiński, T., et al. ....	233
Nag, B.R., see Deb Roy, M. ....	189
Nešpůrek, S., Širka, B.: Charge Carrier Photogeneration in Thin Films of Iodoform .....	223
Oepen, H.P., see Kirschner, J., et al. ....	177
Ostrowsky, D.B., see Falco, C., et al. ....	23
Peschel, W., Kuhnert, R., Schulz, M.: Photoconductivity in Ion-Implanted Thin Films of Si: In and Si:Ti .....	59
Ploog, K., see Künzel, H., et al. ....	73
Przybylińska, H., see Godlewski, M., et al. ....	105
Räsänen, J.: Annealing Behaviour of C-, N-, Mg-, Al-, and P-Implanted Si and Ge .....	87
Regazzoni, C., see Aldi, G., et al. ....	51
Sachs, G., see Dormann, E., et al. ....	227
Schneider, J., see Windscheif, J., et al. ....	47
Schnitzke, K., see Krause, N., et al. ....	67
Schnitzke, K., see Uzel, Y., et al. ....	185
Schulz, M., see Peschel, W., et al. ....	59
Schwoerer, M., see Dormann, E., et al. ....	227
Sigmund, P.: Mechanism of Ion Beam Induced Mixing of Layered Solids .....	43
Širka, B., see Nešpůrek, S. ....	223
Stachel, M., Bömmel, H.E.: Temperature Dependence of the Nuclear Quadrupole Interaction and the Knight Shift in Rhenium Metal .....	27
Stagni, L., Lizzio, R.: Shape Effects in the Interaction Between an Edge Dislocation and an Elliptical Inhomogeneity ..	217
Stöcklein, W., see Dormann, E., et al. ....	227
Stoll, H.: Vacancy Noise Measurements in Metals: Calculation of the Power Spectrum .....	117
Stritzker, B., see Hofer, W.O., et al. ....	83
Swanson, L.W., see Kang, N.K. ....	95
Uzel, Y., see Krause, N., et al. ....	67
Uzel, Y., Schnitzke, K., Krause, N.: Improvement of the Polishing Treatment for Niobium Surfaces of Superconducting Cavity Resonators .....	185
Vitali, G., Zammit, U., Marinelli, M., Bertolotti, M.: Low-Power Multi-Pulse Laser Annealing of $\alpha$ -Ge .....	161

Wagner, D., see Bäuerle, D., et al. ....	147	Wosiński, T., Morawski, A., Figielski, T.: Arsenic Antisite Defects as the Main Electron Traps in Plastically Deformed GaAs .....	233
Wang, W., see Wang, Y., et al. ....	123	Zammit, U., see Vitali, G., et al. ....	161
Wang, Y., Wang, W., Lee, Y.: The X-Ray Diffraction Intensity of Cyclically Loaded Al .....	123	Zeeuw, W.C. de, see Welzenis, R.G. van .....	151
Weber, E.R., see Conzelmann, H., et al. ....	169		
Welzenis, R.G. van, Zeeuw, W.C. de: Impact Ionisation in <i>n</i> -Type InSb at 77 K .....	151		
Wettling, W., see Jantz, W., et al. ....	109		
Windscheif, J., Ennen, H., Kaufmann, U., Schneider, J., Kimura, T.: Annealing Behaviour of the 0.8 eV Luminescence in Undoped Semiinsulating GaAs. ....	47	Indexed in Current Contents	

